

1st probe card

Wafer ID: 07G5, 05A4

Start date: 2024-06-07

There were 181 total error messages and 103 actual errors in 2 wafer(s). 34 were repeats and will not be shown below.

Number of scan chain errors: 14

Number of analog scan failures: 2

Number of digital scan failures: 11

Number of VDD errors: 4

Number of chips with dead pixels: 13

Number of DAQ function program terminations: 1

Number of programming errors: 1

Number of DAQ digital scan errors: 6

Number of DAC calibration errors: 2

Number of temperature measurement errors: 3

Number of LDO measurement errors: 2

Number of IREF trimming failures: 2

Number of threshold scan failures: 2

Number of overvoltage trip errors: 3

Number of data merging errors: 2

36 chip(s) did not complete testing.

Total number of dead pixels: 35 (of 290304 in 2 wafer(s))

Other errors (0):

